

NWL200 Series

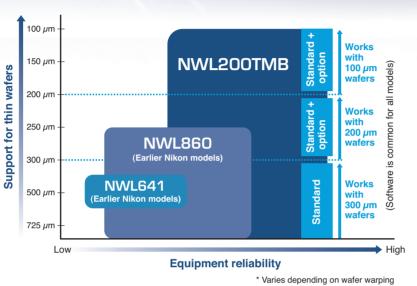
Wafer Loaders for IC Inspection Microscopes



Nikon's proprietary technology ensures reliable loading of ultra-thin 100 µm wafers

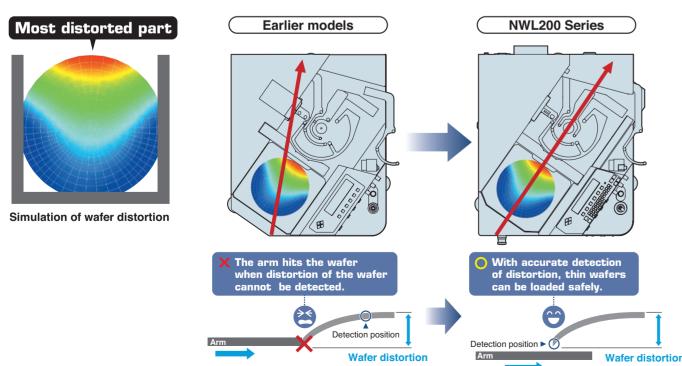
Highly reliable loading suitable for next-generation semiconductors

Nikon's outstanding proprietary technology makes the NWL200 Series the first lineup of wafer loaders for inspection microscopes capable of loading 100 µm thin wafers. The SEMI S2/S8 approved NWL200 Series can load ultra-thin wafers with a thinness of as little as 100 µm. This high level of safety and reliability meets all of the requirements for inspection of the latest wafers.



Improved wafer-sensing functions

Since thin wafers can undergo significant distortion in the carrier, the arm may damage them if the position sensors are not accurate. In the past, it was difficult for sensors to read distortion of the wafers accurately, but with optimized arrangement of the wafer sensor beams, the NWL200 Series can accurately detect the shape of thin wafers in the cassette. Further, when a wafer is placed on a microscope stage, the notch and orientation can be adjusted by 90°.



High throughput

The non-contact centering mechanism makes it possible to perform alignment quickly and accurately. The multi-arm system also allows loading and unloading of wafers with complete precision, increasing the overall efficiency of transfer and wafer exchange. This dramatically decreases cycle times, achieving high levels of throughput.

High reliability

Should an error occur, an error message is displayed on the LCD panel. Even when the power is turned off, the vacuum chuck of the macro inspection mechanism stays on. If a problem occurs, wafers on the loader can be returned to the carrier without the use of tweezers.

Elegant ergonomic design

To assure operation in a natural posture, ergonomic efficiency is designed into every aspect of the system. Operation keys and knobs are located within easy reach of the operator, so that operation requires minimum movement of the hand or eye. The wafer carriers are located at the front and 35° to the left of the operator, making it easy to load carriers and to check the wafers inside the carriers visually.

Mix and match options for a range of applications

External communication functions

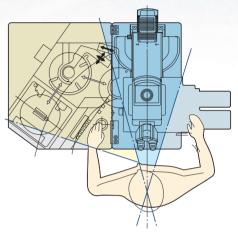
With external communication functions, the NWL200 can be connected to a host computer and built into a network. The system can transfer data from inspection results online over an RS-232C link, and be operated remotely

Comprehensive capabilities

Combined with the Digital Sight Series microscope digital camera and the NIS-Elements imaging software, the system offers comprehensive multidimensional image capture, measurement and analysis capabilities.



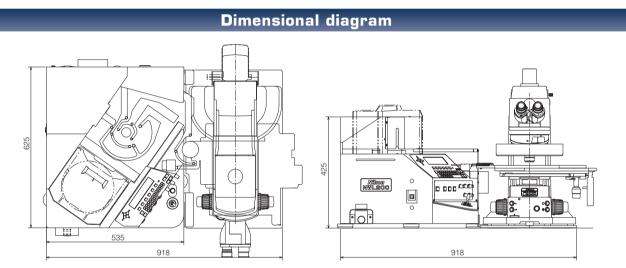




Specifications

Compatible wafer size	Diameter	ø200 mm / ø150 mm *1
	Minimum Thickness (Standard)	300 μm
	Minimum Thickness (Option)	100 µm
Compatible carrier		SEMI 25 (26) wafer carrier *2
Centering		Non-contact, photoelectric sensors
Notch/orientation flat detection		Non-contact, photoelectric sensors
Operation/display section		Wafer slot buttons / interactive LCD interface
External dimensions (WxDxH)		535 x 626 x 350 mm
Weight		50 kg
Safety standards		Electrical safety: CE mark compatible SEMI: S2-0706, S8-0307, F47 compatible Laser safety: FDA Class 1
Utilities		Power supply: AC 100-240 V, 50/60 Hz, 1.5 A-0.7 A Vacuum: -80 kPa Connection tube diameter: ø6 mm

*1: For ø125 mm wafers and non-silicon wafers, please contact Nikon. *2: For other carriers, please contact Nikon. *Optional special wafer loader is also available. Please contact Nikon for detail.



Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. January 2024 ©2008-2024 NIKON CORPORATION

N.B. Export of the products* in this catalog is controlled under the Japanese Foreign Exchange and Foreign Trade Law. Appropriate export procedures shall be required in case of export from Japan. *Products: Hardware and its technical information (including software) Class 1 Laser Product

WARNING TO ENSURE CORRECT USAGE, READ THE CORRESPONDING MANUALS CAREFULLY BEFORE USING THE EQUIPMENT.



NIKON CORPORATION 1-5-20, Nishio, Shinagawa-ku, Tokyo 140-8601, Japan phone: +81-3-6743-5742 fax: +81-3-6410-7252 https://industry.nikon.com/

PT. NIKON INDONESIA INDONESIA phone: +62-213-873-5005 fax: +62-213-873-5006 E-mail: PTN.Instruments@nikon.com NIKON SALES (THAILAND) CO., LTD. THAILAND phone: +66-2633-5100 fax: 66-2633-5191

NIKON METROLOGY EUROPE NV

Interleuvenlaan 86 8-3001 Leuven, Belgium phone: +32-16-74-01-00 fax: +32-16-74-01-03 E-mail: Sales.Europe.NM@nikon.com https://industry.nikon.com/en-gb/ NIKON METROLOGY UK LTD. UNITED KINGDOM phone: +44-1332-811-349 fax: +44-1332-639-881 E-mail: Sales.UK.NM@nikon.com NIKON METROLOGY SARL

FRANCE phone: +33-1-60-86-09-76 fax: +33-1-60-86-57-35 E-mail: Sales.France.NM@nikon.com

NIKON METROLOGY GMBH GERMANY phone: +49-211-45-44-69-51 E-mail: Sales.Germany.NM@nikon.com NIKON INSTRUMENTS S.p.A. ITALY phone: +39-055-300-96-01 fax: +39-055-30-09-93

NIKON METROLOGY, INC.

12701 Grand River Road, Brighton, MI 48116 U.S.A. phone: +1-810-220-4360 fax: +1-810-220-4300 E-mail: Sales.NM-US@nikon.com https://industry.nikon.com/en-us/ NIKON METROLOGY - MÉXICO E-mail: Sales.NM-MX@nikon.com NIKON PRECISION (SHANGHAI) CO., LTD.

CHINA (shanghai branch) phone: +86-21-6841-2050 fax: +86-21-6841-2060 (Beijing branch) phone: +86-10-5831-2028 fax: +86-10-5831-2026 (Guangzhou branch) phone: +86-20-3882-0551 fax: +86-20-3882-0580

NIKON INSTRUMENTS KOREA CO., LTD. KOREA phone: +82-2-6288-1900 fax: +82-2-555-4415 NIKON SINGAPORE PTE. LTD. SINGAPORE phone: +65-6559-3651 fax: +65-6559-3668 E-mail: NSG.Industrial-sales@nikon.com

Code No. 2CE-KCAH-7

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